



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/632,273
Filing Date July 31, 2003
Inventor..... Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Group Art Unit..... 2829
Examiner Russell M. Kobert
Attorney's Docket No. MI22-2379
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patent listed on the attached Form PTO-1449. No admission is made regarding whether the submitted reference is prior art.

Citation of this reference is respectfully requested.

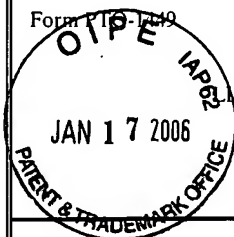
Respectfully submitted,

Date: 1-16-06



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Form PTO-1249

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-2379SERIAL NO.
10/632,273LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Warren M. FarnworthFILING DATE
July 31, 2003GROUP
2829

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,201,992	4/93	Marcus, et al.	156	643	
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AM							
AN							
AO							
AP							
AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR		
AS		

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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